

## FDS6990S

### Dual 30V N-Channel PowerTrench<sup>o</sup> SyncFET<sup>™</sup>

#### **General Description**

The FDS6990S is designed to replace a dual SO-8 MOSFET and two Schottky diodes in synchronous DC:DC power supplies. This 30V MOSFET is designed to maximize power conversion efficiency, providing a low  $R_{\rm DS(ON)}$  and low gate charge. Each MOSFET includes integrated Schottky diodes using Fairchild's monolithic SyncFET technology. The performance of the FDS6990S as the low-side switch in a synchronous rectifier is similar to the performance of the FDS6990A in parallel with a Schottky diode.

#### Applications

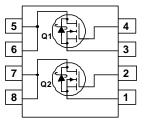
- DC/DC converter
- Motor drives

# SO-8 Pin 1 Pin 1

## Features

• 7.5A, 30 V.  $R_{DS(ON)} = 22 \text{ m}\Omega @ V_{GS} = 10 \text{ V}$  $R_{DS(ON)} = 30 \text{ m}\Omega @ V_{GS} = 4.5 \text{ V}$ 

- Includes SyncFET Schottky diode
- Low gate charge (11 nC typical)
- + High performance trench technology for extremely low  $$R_{\text{DS}(\text{ON})}$$
- High power and current handling capability



#### Absolute Maximum Ratings TA=25°C unless otherwise noted

Symbol	Parameter			Ratings	Units
V <sub>DSS</sub>	Drain-Source Voltage			30	V
V <sub>GSS</sub>	Gate-Source	e Voltage		±20	V
I <sub>D</sub>	Drain Curren	t – Continuous	(Note 1a)	7.5	A
		– Pulsed		20	
P <sub>D</sub>	Power Dissipation for Dual Operation			2	
	Power Dissipation for Single Operation (Note 1a)			1.6	
			(Note 1b)	1	
			(Note 1c)	0.9	
T <sub>J</sub> , T <sub>STG</sub>	Operating ar	nd Storage Junction Tempe	erature Range	-55 to +150	
Therma	I Charact	teristics			<u>.</u>
$R_{ ext{ hetaJA}}$	Thermal Resistance, Junction-to-Ambient (Note 1a)			78	°C/W
R <sub>eJC</sub>	Thermal Resistance, Junction-to-Case (Note 1)			40 °C/	
Packag	e Marking	g and Ordering I	nformation		
Device Marking		Device	Reel Size	Tape width	Quantity
FDS6990S		FDS6990S	13"	12mm	2500 units

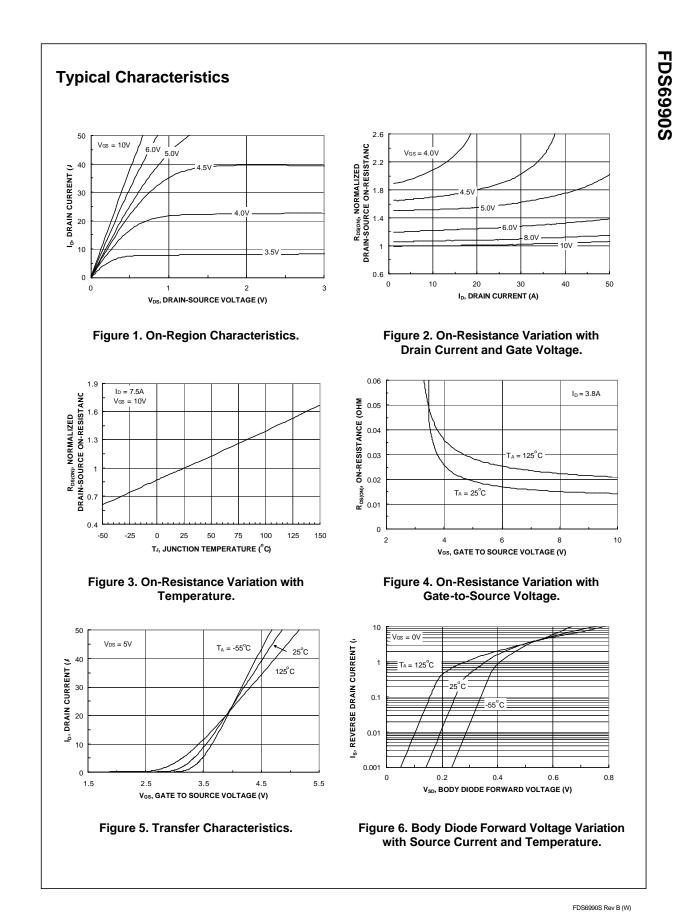
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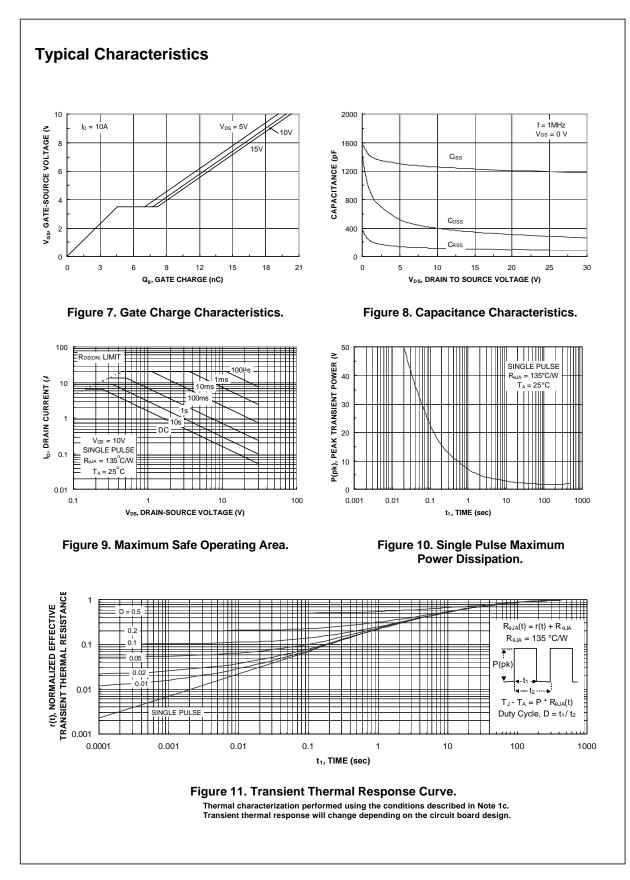
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	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics					
BV <sub>DSS</sub>	Drain–Source Breakdown Voltage	$V_{GS} = 0 V$ , $I_D = 1 mA$	30			V
<u>ΔBV<sub>DSS</sub></u> ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	$I_D = 1$ mA, Referenced to 25°C		23		mV/°C
DSS	Zero Gate Voltage Drain Current	$V_{\text{DS}} = 24 \text{ V}, \qquad V_{\text{GS}} = 0 \text{ V}$			500	μA
GSSF	Gate-Body Leakage, Forward	$V_{GS} = 20 \text{ V}, \qquad V_{DS} = 0 \text{ V}$			100	nA
I <sub>GSSR</sub>	Gate-Body Leakage, Reverse	$V_{GS} = -20 \text{ V} \qquad V_{DS} = 0 \text{ V}$			-100	nA
On Chara	acteristics (Note 2)					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 1 \text{ mA}$	1	2.2	3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	$I_D = 1$ mA, Referenced to 25°C		-6		mV/°C
R <sub>DS(on)</sub>	Static Drain–Source On–Resistance	$ \begin{array}{c} V_{GS} = 10 \ V, \ I_D = 7.5 \ A \\ V_{GS} = 10 \ V, \ I_D = 7.5 \ A, \ T_J = 125^\circ C \\ V_{GS} = 4.5 \ V, \ I_D = 6.5 \ A \end{array} $		17.5 27 24	22 35 30	mΩ
I <sub>D(on)</sub>	On-State Drain Current	$V_{GS} = 10 \text{ V}, \qquad V_{DS} = 5 \text{ V}$	20			Α
g <sub>FS</sub>	Forward Transconductance	$V_{DS} = 15 \text{ V}, \qquad I_D = 10 \text{ A}$		22		S
Dvnamic	Characteristics					
C <sub>iss</sub>	Input Capacitance	$V_{DS} = 15 \text{ V},  V_{GS} = 0 \text{ V},$		1233		pF
C <sub>oss</sub>	Output Capacitance	f = 1.0 MHz		344		pF
C <sub>rss</sub>	Reverse Transfer Capacitance	_		106		pF
	g Characteristics (Note 2)		1			
t <sub>d(on)</sub>	Turn-On Delay Time	$V_{DS} = 15 \text{ V}, \qquad I_D = 1 \text{ A},$		8	16	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{\text{GS}} = 10 \text{ V}, \qquad R_{\text{GEN}} = 6 \Omega$		5	10	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	-		25	40	ns
t <sub>f</sub>	Turn–Off Fall Time	—		11	20	ns
Q <sub>g</sub>	Total Gate Charge	$V_{DS} = 15 \text{ V}, \qquad I_D = 10 \text{ A},$		11	16	nC
Q <sub>gs</sub>	Gate-Source Charge	$V_{GS} = 5 V$		5		nC
Q <sub>qd</sub>	Gate-Drain Charge	_		4		nC
0	viras Diado Charactoristias	and Maximum Patings		l		l
	Durce Diode Characteristics		1		2.9	^
S	Drain–Source Diode Forward					A
V <sub>SD</sub>	Voltage	$V_{GS} = 0 V$ , $I_S = 2.9 A$ (Note 2)		0.5	0.7	V
t <sub>rr</sub>	Diode Reverse Recovery Time	I <sub>F</sub> = 10A		17		nS
Q <sub>rr</sub>	Diode Reverse Recovery Charge	$d_{iF}/d_t = 300 \text{ A}/\mu \text{s}$ (Note 3)		12.5		nC

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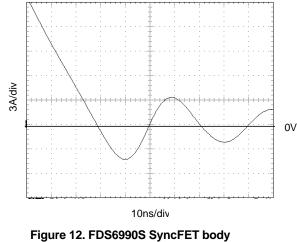


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#### Typical Characteristics (continued)

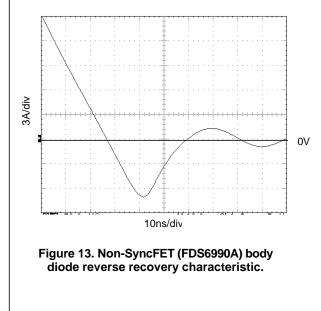
## SyncFET Schottky Body Diode Characteristics

Fairchild's SyncFET process embeds a Schottky diode in parallel with PowerTrench MOSFET. This diode exhibits similar characteristics to a discrete external Schottky diode in parallel with a MOSFET. Figure 12 shows the reverse recovery characteristic of the FDS6990S.



diode reverse recovery characteristic.

For comparison purposes, Figure 13 shows the reverse recovery characteristics of the body diode of an equivalent size MOSFET produced without SyncFET (FDS6990A).



Schottky barrier diodes exhibit significant leakage at high temperature and high reverse voltage. This will increase the power in the device.

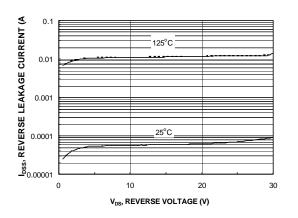


Figure 14. SyncFET body diode reverse leakage versus drain-source voltage and temperature.



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